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Du, T.C.; Wong, J.; Lee, M.;  
e-Commerce Technology, 2004. CEC 2004. Proceedings. IEEE International Conference on  
6-9 July 2004 Page(s):170 - 177.  
Digital Object Identifier 10.1109/ICECT.2004.1319731  
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2. Detecting and representing relevant Web deltas in WHOWEDA

Bhowmick, S.S.; Madria, S.K.; Wee Keong Ng;  
Knowledge and Data Engineering, IEEE Transactions on  
Volume 15, Issue 2, March-April 2003 Page(s):423 - 441  
Digital Object Identifier 10.1109/TKDE.2003.1185843

[AbstractPlus](#) | [References](#) | Full Text: [PDF\(2779 KB\)](#) IEEE JNL

3. Cost-benefit analysis of Web bag in a Web warehouse

Bhowmick, S.S.; Madria, S.; Wee-Kong Ng; Ee-Peng Lim;  
Database Engineering and Applications, 1999. IDEAS '99. International Symposium Proceedings  
2-4 Aug. 1999 Page(s):34 - 42  
Digital Object Identifier 10.1109/IDEAS.1999.787249

[AbstractPlus](#) | Full Text: [PDF\(188 KB\)](#) IEEE CNF

4. Production datawarehouse and software toolset to support productivity improvement activities

Saroya, M.; Halmel, S.;  
Advanced Semiconductor Manufacturing Conference and Workshop, 1999 IEEE/SEMI  
8-10 Sept. 1999 Page(s):183 - 187  
Digital Object Identifier 10.1109/ASMC.1999.798217

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